


<b>Search Notes</b>  	<b>Application/Control No.</b>  10520028	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAGAWA ET AL.
	<b>Examiner</b>  LEILA MALEK	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	260,316,267,295	2/9/2010	L.M.
455	553.1,13.4,522,127.1	2/9/2010	L.M.

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted M. Ghayour, EAST, IEEE, Inventor Name Search	2/9/2010	L.M.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	260,316,267	2/9/2010	L.M.
455	553.1,13.4,522,127.1	2/9/2010	L.M.

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